

<b>Notice of References Cited</b>	Application/Control No. 10/669,926	Applicant(s)/Patent Under Reexamination BEAUPRE, JEAN M.	
	Examiner VICTORIA W. CHEN	Art Unit 3739	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0023257 A1	01-2003	Ishikawa et al.	606/169
	B	US-			
	C	US-			
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